SiNi

AFM Tip

SHAPE	HEIGHT	RADIUS	HALF CONE ANGLE
Pyramid	12 µm (10 – 14 µm)*	15 nm	35° (macroscopic)

4 AFM Cantilevers

Short Cantilever		Long Cantilever	
Shape	Triangle	**Shape**	Triangle
Force Constant	0.27 N/m	**Force Constant**	0.06 N/m
Resonance Frequency	30 kHz	**Resonance Frequency**	10 kHz
Length	100 µm (90 – 110 µm)*	**Length**	200 µm (190 – 210 µm)*
Width	16 µm (11 – 21 µm)*	**Width**	30 µm (25 – 35 µm)*
Thickness	520 nm (470 – 570 nm)*	**Thickness**	520 nm (470 – 570 nm)*

* typical range

Coating

Gold/Chromium on detector side of the cantilever, 70 nm thick

Alignment Grooves

none

Additional Info

This competitively priced silicon nitride AFM probe features:

— 2 silicon nitride AFM cantilevers for soft contact mode with two different lengths and force constants mounted on each side of a standard silicon support chip
— silicon nitride wedge AFM tip
— overall AFM tip height of 12 µm (effective > 800 nm) with a double tip spacing of 4.5 µm
— macroscopic half cone angle of 35°
— 450 micron thick silicon holder chip